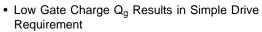


N-Channel 650 V (D-S)MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	650				
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V 2.1				
Q _g (Max.) (nC)	48				
Q _{gs} (nC)	12				
Q _{gd} (nC)	19				
Configuration	Single				

FEATURES

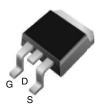


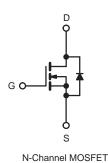


• Improved Gate, Avalanche and Dynamic dV/dt Ruggedness

- Fully Characterized Capacitance and Avalanche Voltage and Current
- Compliant to RoHS directive 2002/95/EC







PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	650	.,	
Gate-Source Voltage			V_{GS}	± 30	V	
Continuous Drain Currente	V _{GS} at 10 V	T _C = 25 °C	1	4.5	А	
Continuous Drain Current	VGS at 10 V	T _C = 100 °C	I _D	4.2		
Pulsed Drain Current ^a			I _{DM}	18		
Linear Derating Factor				0.48	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	325	mJ	
Repetitive Avalanche Current ^a			I _{AR}	4	Α	
Repetitive Avalanche Energy ^a		E _{AR}	6	mJ		
Maximum Power Dissipation $T_C = 25 ^{\circ}C$			P_D	60	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.8	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	- °C	
Soldering Recommendations (Peak Temperature) ^d	ns (Peak Temperature) ^d for 10 s			300		
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Forque				1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T $_J$ = 25 °C, L = 24 mH, R $_G$ = 25 Ω , I $_{AS}$ = 3.2 A (see fig. 12). c. I $_{SD}$ ≤ 3.2 A, dI/dt ≤ 90 A/ μ s, V $_{DD}$ ≤ V $_{DS}$, T $_J$ ≤ 150 °C.

- d. 1.6 mm from case.
- e. Drain current limited by maximum junction temperature.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	65	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	2.1	C/VV	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	V _{GS} = 0 V, I _D = 250 μA		-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I _D = 1 mA ^d	-	670	-	mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	,	$V_{GS} = \pm 30 \text{ V}$	ı	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		= 650 V, V _{GS} = 0 V V, V _{GS} = 0 V, T _J = 125 °C	-	-	25 250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 3.1 A ^b	-	2.1	-	Ω
Forward Transconductance	9fs		= 50 V, I _D = 3.1 A	3.9	-	-	S
Dynamic							
Input Capacitance	C _{iss}		V _{GS} = 0 V,	-	1417	-	
Output Capacitance	C _{oss}		$V_{DS} = 25 \text{ V},$	-	177	-	1
Reverse Transfer Capacitance	C _{rss}	f = 1	f = 1.0 MHz, see fig. 5		7.0	-	
Output Capacitance	C _{oss}		V _{DS} = 1.0 V, f = 1.0 MHz	-	1912	-	pF -
		$V_{GS} = 0 V$	V _{DS} = 520 V, f = 1.0 MHz	-	48	-	
Effective Output Capacitance	Coss eff.	V _{DS} = 0 V to 520 V ^c		-	84	-	
Total Gate Charge	Qg			-	-	48	
Gate-Source Charge	Q_{gs}	V _{GS} = 10 V	$V_{GS} = 10 \text{ V}$ $I_D = 3.2 \text{ A}, V_{DS} = 400 \text{ V}$		-	12	nC
Gate-Drain Charge	Q_{gd}	see fig. 6 and 13 ^b		-	-	19	
Turn-On Delay Time	t _{d(on)}			-	14	-	
Rise Time	t _r		$V_{DD} = 325 \text{ V}, I_D = 3.2 \text{ A}$ $R_G = 9.1 \Omega, R_D = 62 \Omega,$ see fig. 10 ^b		20	-	1
Turn-Off Delay Time	t _{d(off)}	$R_{G} =$			34	-	ns
Fall Time	t _f	1		-	18	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	showing the	/ : T/		-	4	A
Pulsed Diode Forward Current ^a	I _{SM}	p - n junction diode		i	-	21	
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 3.2 A, V _{GS} = 0 V ^b		ı	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 3.2 A, dI/dt = 100 A/μs ^b		-	493	739	ns
Body Diode Reverse Recovery Charge	Qrr			-	2.1	3.2	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)					L _D)

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300~\mu s$; duty cycle $\leq 2~\%$. c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .
- d. t = 60 s, f = 60 Hz.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

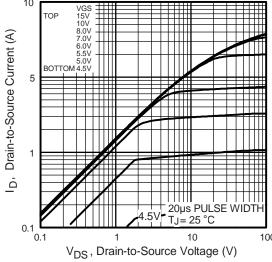


Fig. 1 - Typical Output Characteristics

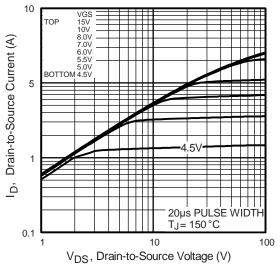


Fig. 2 - Typical Output Characteristics

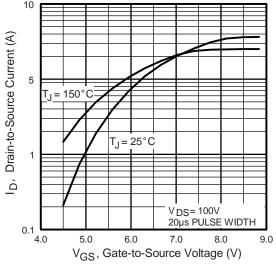


Fig. 3 - Typical Transfer Characteristics

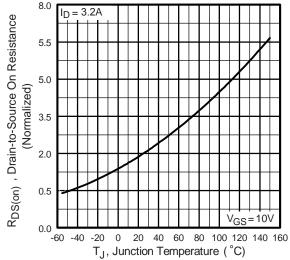


Fig. 4 - Normalized On-Resistance vs. Temperature



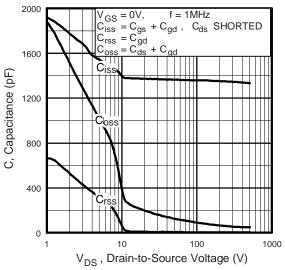


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

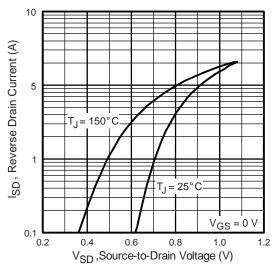


Fig. 7 - Typical Source-Drain Diode Forward Voltage

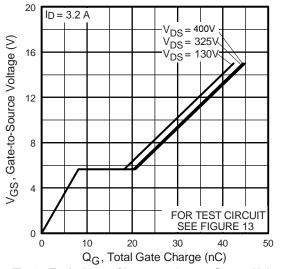


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

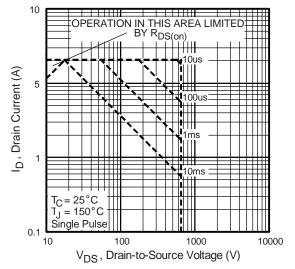


Fig. 8 - Maximum Safe Operating Area



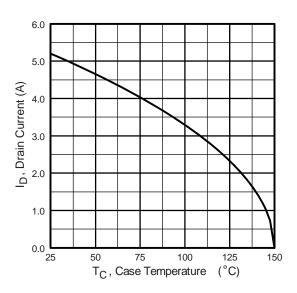


Fig. 9 - Maximum Drain Current vs. Case Temperature

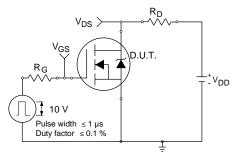


Fig. 10a - Switching Time Test Circuit

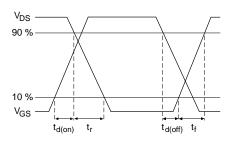


Fig. 10b - Switching Time Waveforms

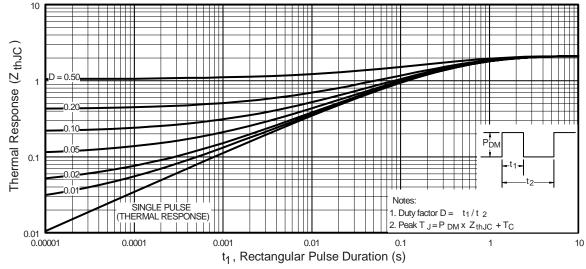


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

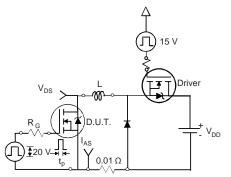


Fig. 12a - Unclamped Inductive Test Circuit

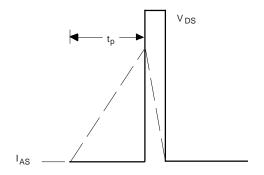


Fig. 12b - Unclamped Inductive Waveforms



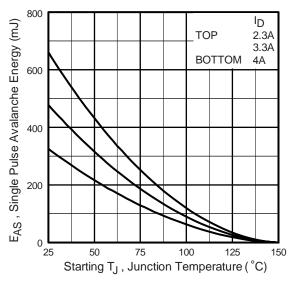


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

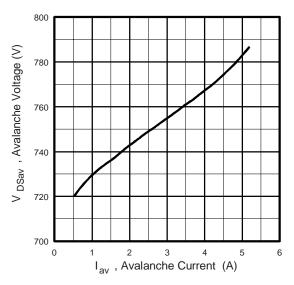


Fig. 12d - Typical Drain-to Source Voltage vs. Avalanche Current

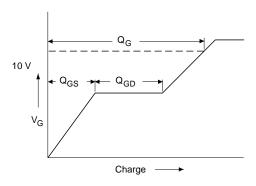


Fig. 13a - Basic Gate Charge Waveform

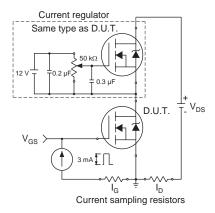
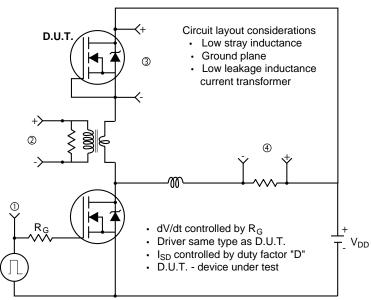
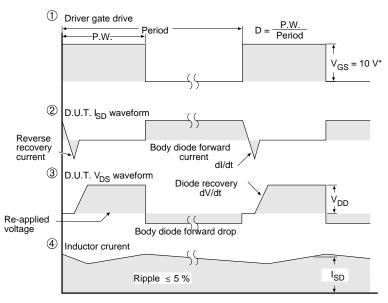


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



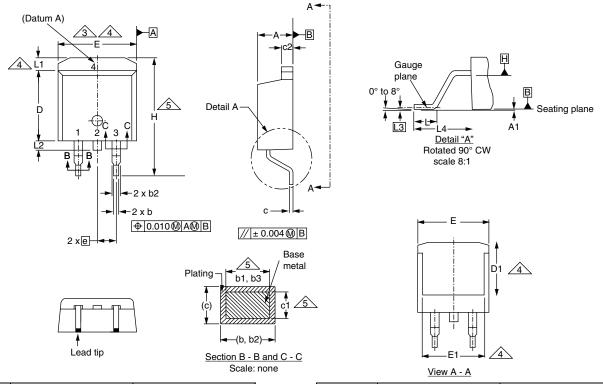


* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel



TO-263AB (HIGH VOLTAGE)



	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.06	4.83	0.160	0.190
A1	0.00	0.25	0.000	0.010
b	0.51	0.99	0.020	0.039
b1	0.51	0.89	0.020	0.035
b2	1.14	1.78	0.045	0.070
b3	1.14	1.73	0.045	0.068
С	0.38	0.74	0.015	0.029
c1	0.38	0.58	0.015	0.023
c2	1.14	1.65	0.045	0.065
D	8.38	9.65	0.330	0.380

	MILLIMETERS		INCHES	
DIM.	MIN.	MAX.	MIN.	MAX.
D1	6.86	-	0.270	-
Е	9.65	10.67	0.380	0.420
E1	6.22	-	0.245	ı
е	2.54 BSC		0.100 BSC	
Н	14.61	15.88	0.575	0.625
L	1.78	2.79	0.070	0.110
L1	-	1.65	-	0.066
L2	-	1.78	-	0.070
L3	0.25 BSC		0.010 BSC	
L4	4.78	5.28	0.188	0.208

ECN: S-82110-Rev. A, 15-Sep-08

DWG: 5970

Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).
- 3. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.
- 4. Thermal PAD contour optional within dimension E, L1, D1 and E1.
- 5. Dimension b1 and c1 apply to base metal only.
- 6. Datum A and B to be determined at datum plane H.
- 7. Outline conforms to JEDEC outline to TO-263AB.

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